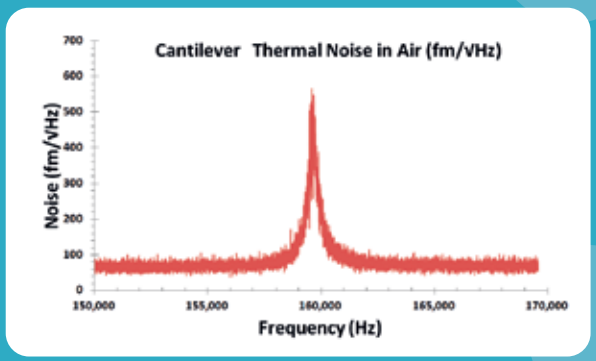
ezAFM™

Atomic Force Microscope

for Research, Education and QC Applications

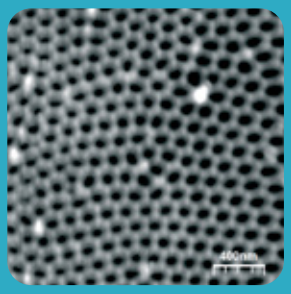
- Innovative technology with superior performance
- Setup under an hour



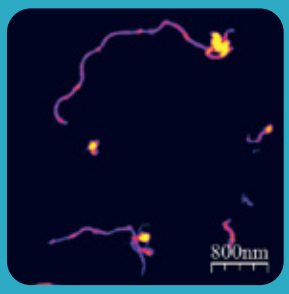
Thermal Noise

NanoMagnetics Instruments

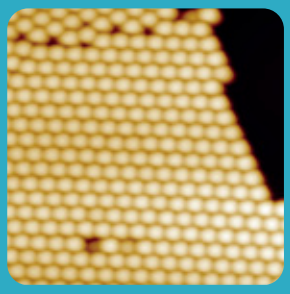
Atomic Force Microscope


Anodic Aluminum Oxide[1]

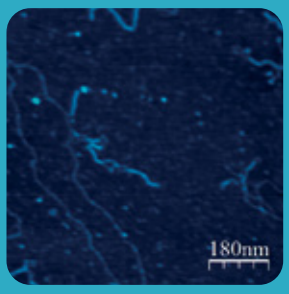
Organic Single Crystal[2]



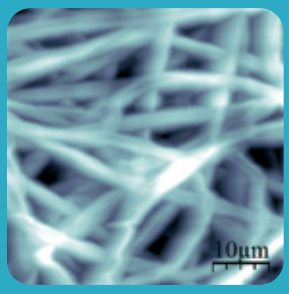
Multi-walled Carbon Nanotubes


Polystyrene Spheres on Si

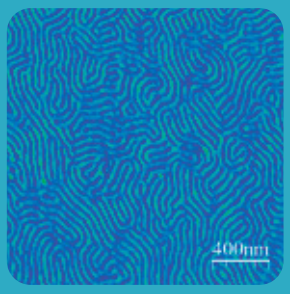

Red Blood Cells



DNA



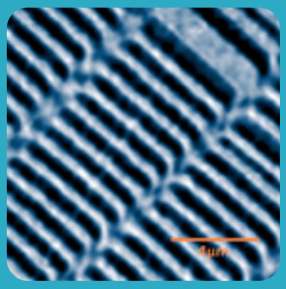
Polycaprolactone Fibers[3]

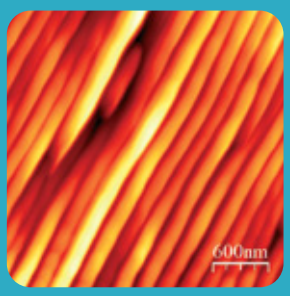


PS-b-PMMA Phase Image[4]

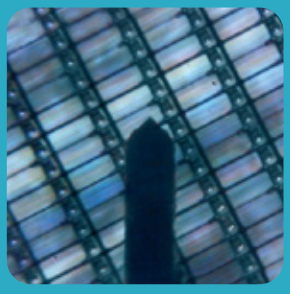
Technical Specifications

- Alignment free cantilevers, commercially available
- 120x120x40 µm or 40x40x4 µm scan range
- Contact, Dynamic/Phase Imaging, Lateral Force & MFM modes
- 65 fm√Hz noise floor
- 2µm resolution integrated optical microscope
- Full HD, 390x230µm FOV, 1920x1080 pixels, 30fps, video camera
- 24Bit ADCs/DACs
- Digital Feedback with FPGA/DSP
- Free software upgrades for lifetime
- Unlimited user license
- USB and WiFi interfaces
- Sample Size, 10x10x5mm (Configurable for unlimited sample size)


MFM Image of HDD



Nanostructured Substrate[5]


Video Microscope Image of Cantilever

Extended Imaging Options

- Scratching Lithography
- Scanning Tunneling Microscopy (ezSTM)
- Liquid Cell

Accessories

- Signal Access Module
- 38 mm stroke XY motorized sample positioner
- 2 mm stroke XY manual sample positioner

(1) Sample courtesy of Dr. Fatih Buyukserin, TOBB University (2) Sample courtesy of Dr. Yasuo Nakayama, Chiba University (3) Sample courtesy of Dr. Aylin Sendemir, Ege University (4) Sample courtesy of Dr. Serdar Onses, Erciyes University (5) Sample courtesy of Dr. Francesco Buatier, Genova University

Suite 290, 266 Banbury Road Oxford OX2 7DL U.K.
Tel: +44 7906 159508 • Fax: +44 870 7620573
www.nanomagnetics-inst.com • info@nanomagnetics-inst.com